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Recent Advances in Reliability and Security in 5G/6G Mobile Networks

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Message from the Guest Editors

Topics of interest include (but are not limited to) the following:

- Innovative Network Architectures for 5G/6G Mobile Network Security.
- Formal Theories and Verification Technologies for 5G/6G Mobile Network Security.
- Lightweight Cryptographic Algorithms and Protocols for 5G/6G Mobile Network.
- Artificial Intelligence (AI) Solutions for Security Issues in 5G/6G Mobile Network.
- Open Source Software (OSS) Security Technologies in 5G/6G Mobile Network.
- Internet of Things (IoT) Security Technologies in 5G/6G Mobile Network.
- Network Slicing Security Technologies for 5G/6G Mobile Network.
- Security and Privacy Preservation Technologies for 5G/6G Mobile Network.
- Innovative Attacks and Defenses Technologies in 5G/6G Mobile Network.
- Cloud Computing and Edge Computing Security Technologies for 5G/6G Mobile Network.











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Message from the Editor-in-Chief

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